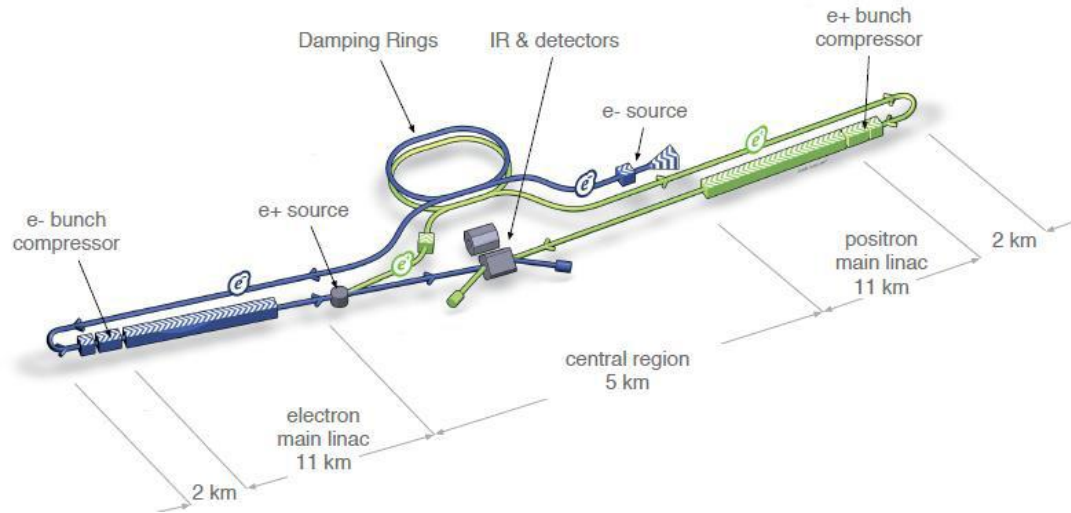


# Test of GEM produced by Fujikura company

M1

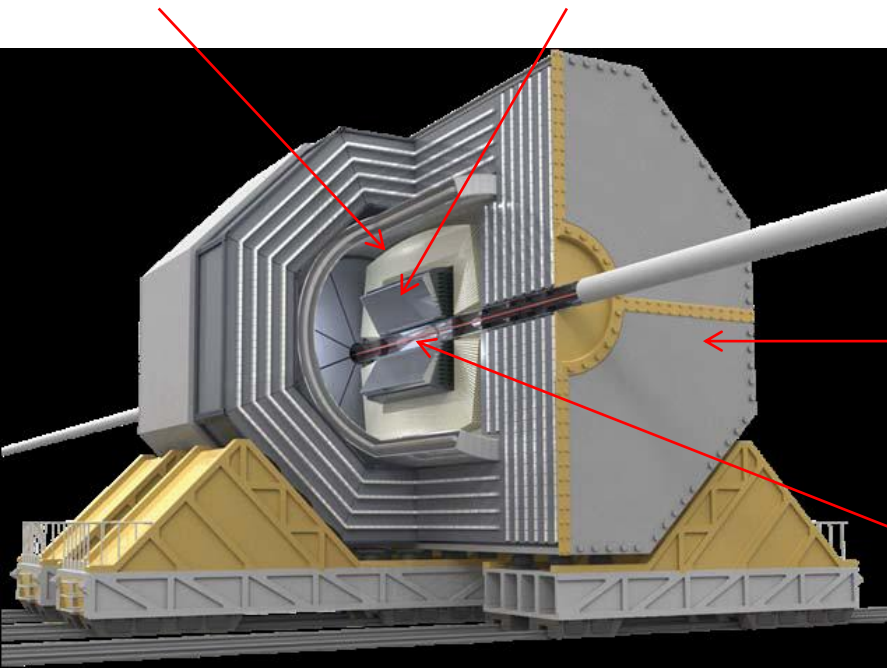
Kazuki Sueta

# ILC (International Linear Collider)



## ILD detector

**Calorimeter Central tracker(TPC)**

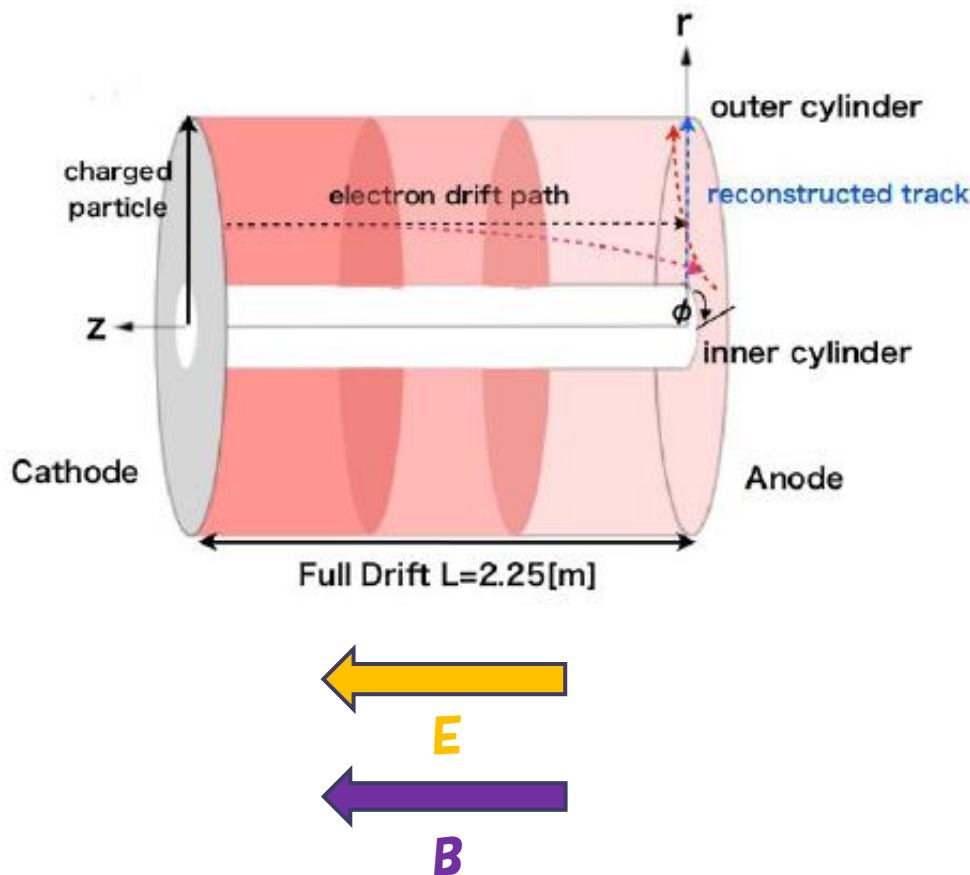


Central tracker of ILD is TPC.  
So we study TPC.

**Muon system**

**Vertex Detector**

# TPC(Time Projection Chamber)

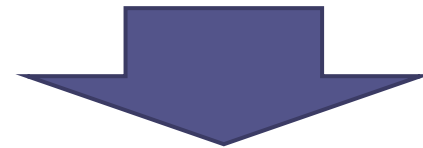


We can reconstruct track by using three parameter  $r$ ,  $r\phi$  and  $Z$ .

How to decide these parameter?

To measure

- $r$   $\phi$ : Position of charge signal  
COG(Center value Of Gravity)
- $Z$ : Drift time of electron

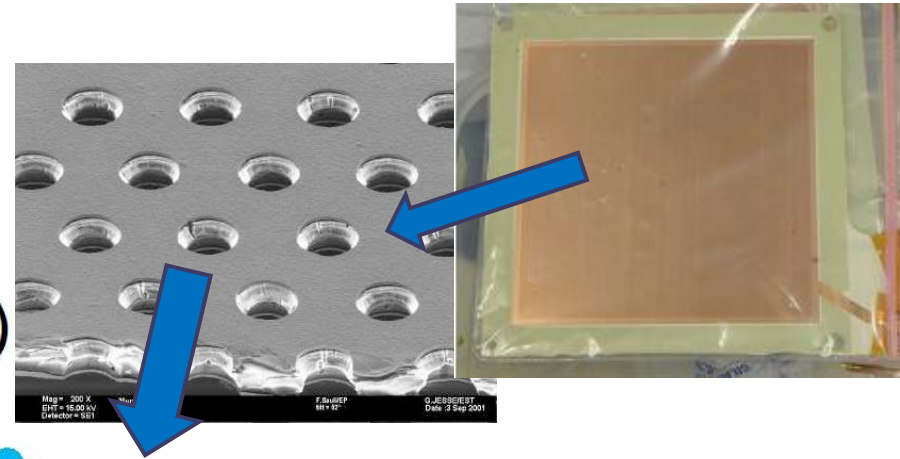
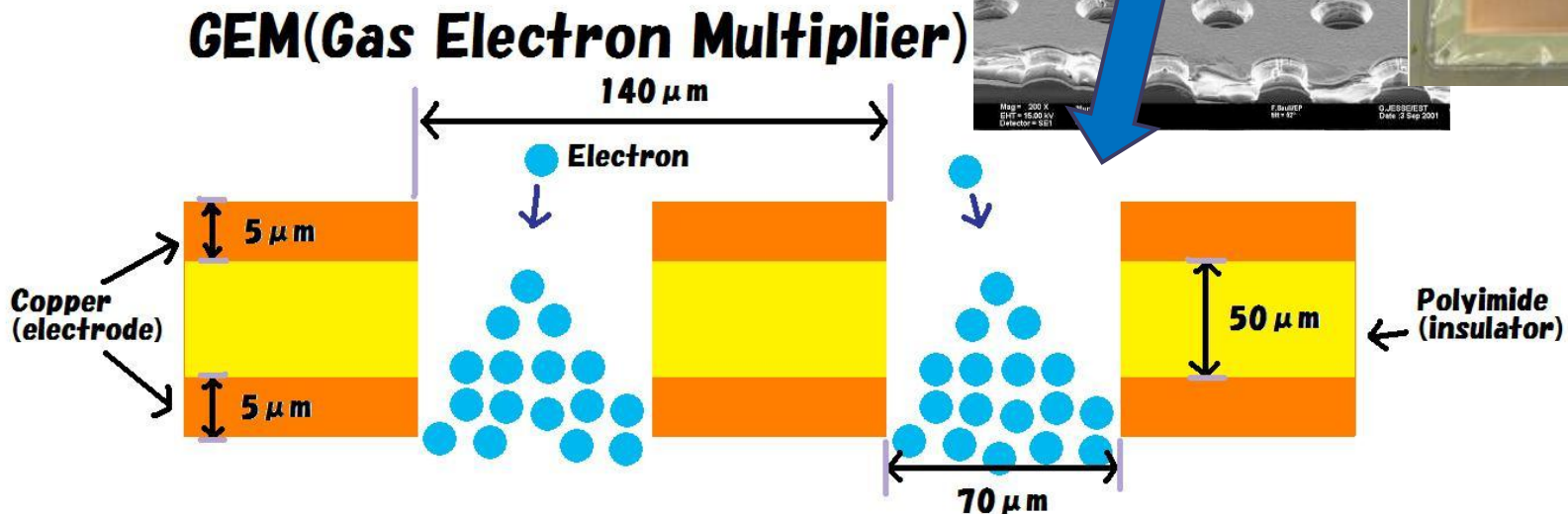


GEM is a one of the candidate for gas multiplication.

# GEM(Gas Electron Multiplier)

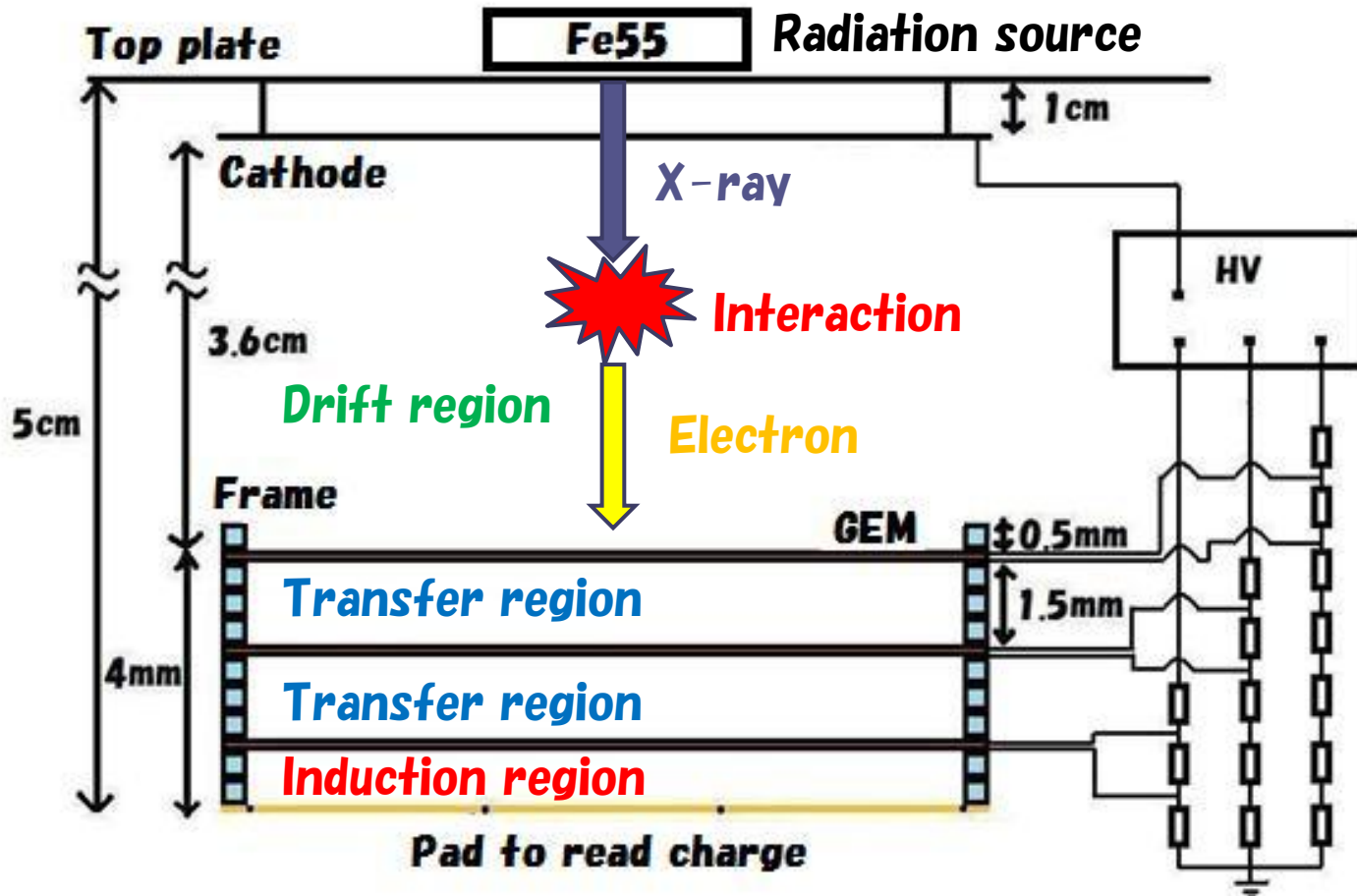
- When (high) voltage difference is applied between upper and lower electrodes, electrons are multiplied.
- We can read charge of electrons.

This figure and two pictures show the GEM produced by Scienergy company.



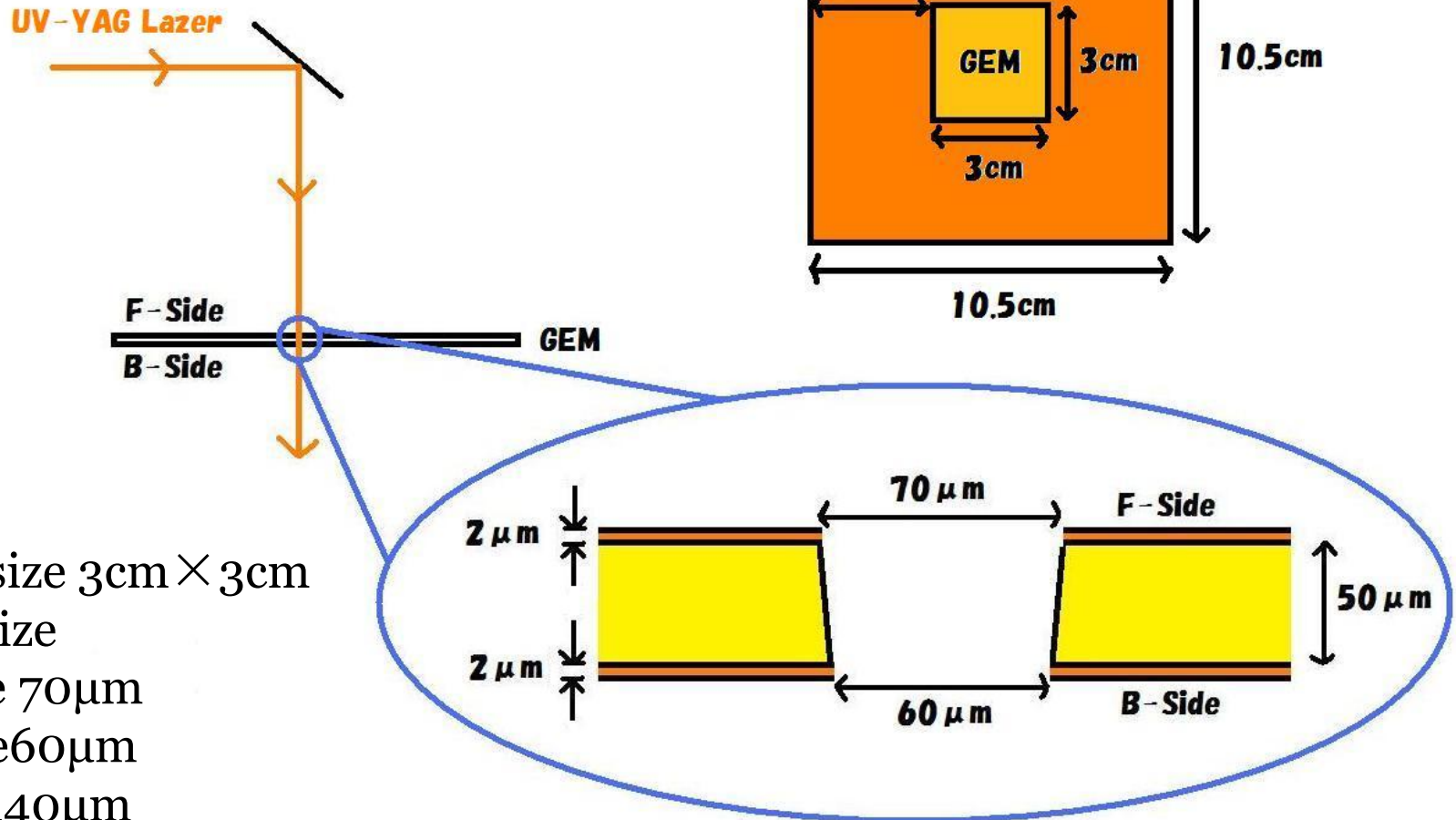
# Test Chamber

- We measure gain of new GEM.
- The chamber is filled with P10 gas(Ar:CH<sub>4</sub>=90:10).
- X-ray interact with gas atom in drift region, and ionized electrons start to drift to GEM.



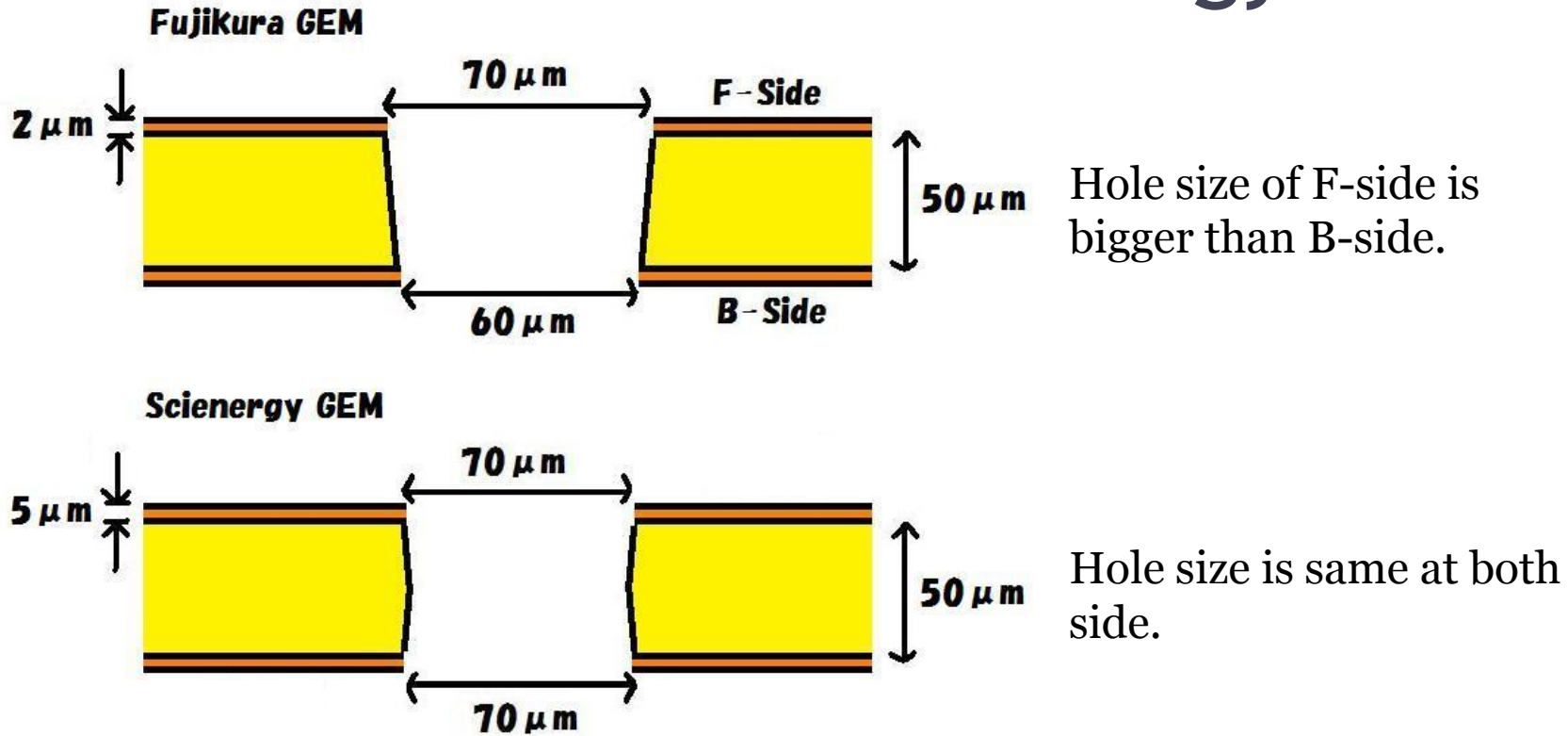
# New GEM produced by Fujikura company

This figure shows new method of making a hole.



- GEM size 3cm × 3cm
- Hole size
  - F-side 70µm
  - B-side 60µm
- pitch 140µm

# Fujikura GEM and Scienergy GEM



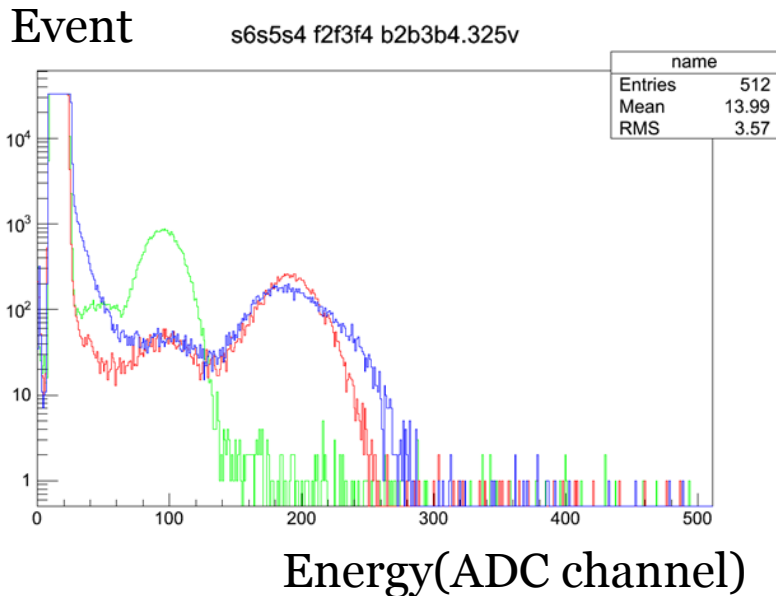
Hole of Scienergy GEM is made by Co<sub>2</sub> laser(thermal process), but Fujikura GEM is made by UV-YAG laser. So these GEMs have different hole size.



We have to check performance of Fujikura GEM.

# Experimental data

Energy spectrum of X-ray

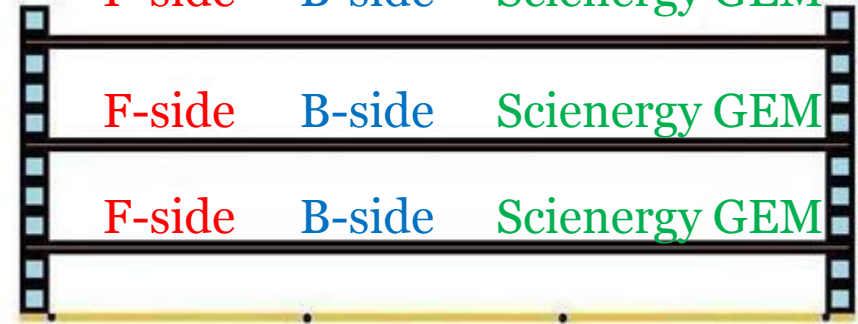


We compared Fujikura GEMs and Scienergy GEMs.

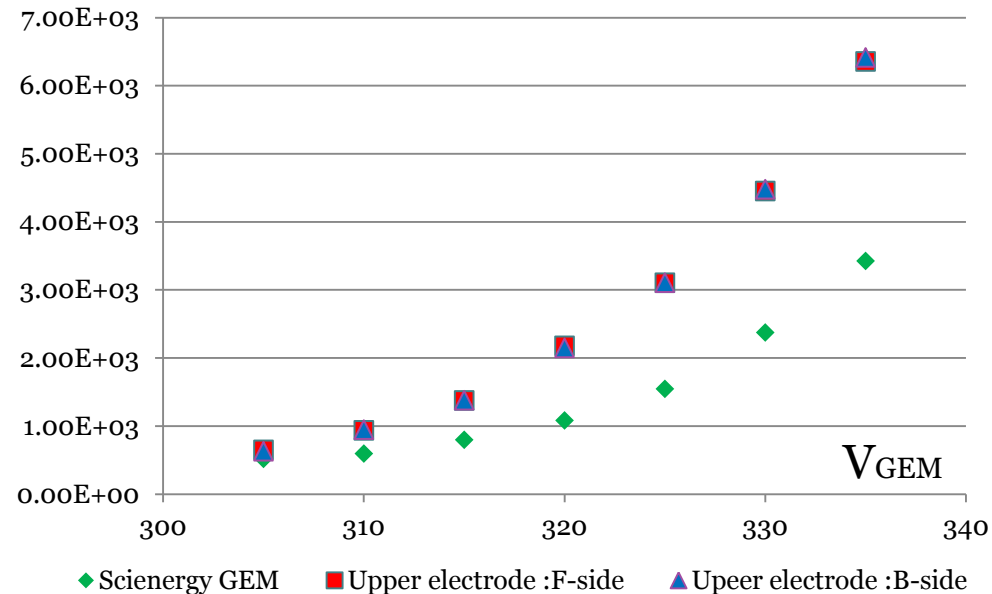
We checked Fujikura GEMs have enough gain .

Comparison condition

① F-side      ② B-side      ③ Scienergy GEM



Gain





# Next

- We checked gain of Fujikura GEM that is made by UV-YAG laser technology.
- UV-YAG laser technology is useful method.



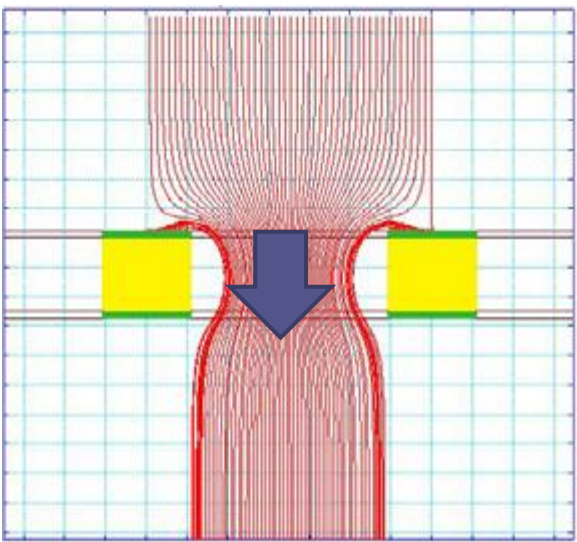
- We want to apply this technology to produce gate GEM.
- Aperture of Gate GEM have to be high, because we want to get good transmission.
- UV-YAG laser technology has high accuracy of making a hole. We expect that we can get high aperture of gate GEM.

# Gating system by GEM

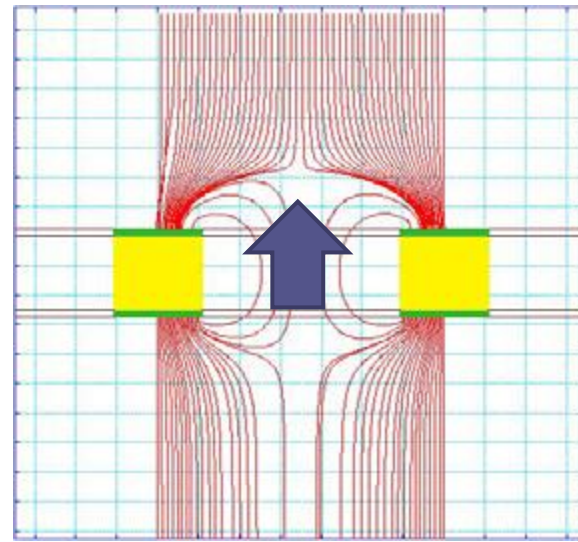
When electrons are multiplied, many ions are produced and go back to drift region and make ion disc. These ions have to be stopped by using gate.

Switching potential

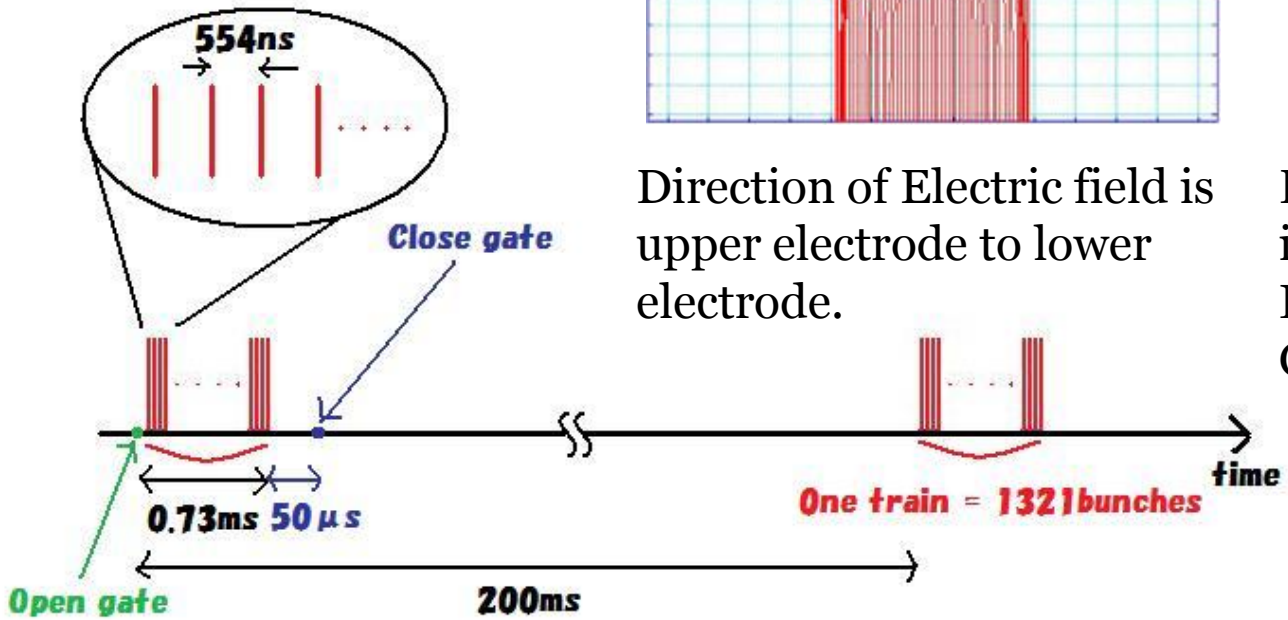
Open



Close



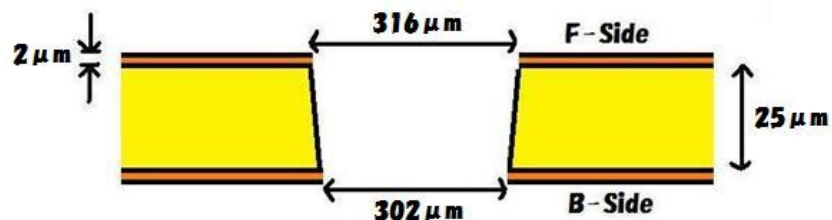
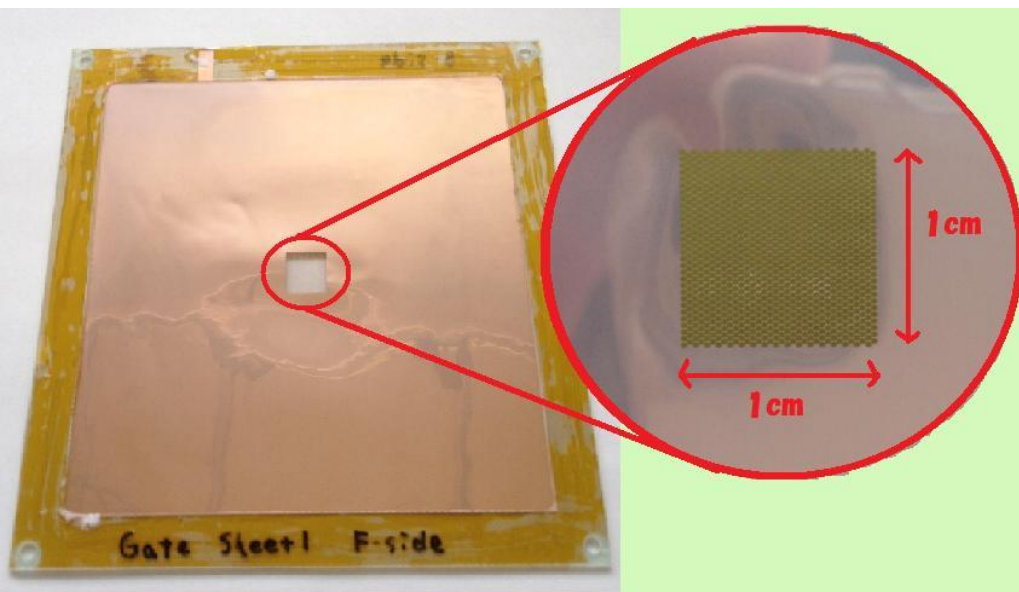
## Beam pulse structure



Direction of Electric field is upper electrode to lower electrode.

Direction of Electric field is reversed. Ions are stopped by gate GEM.

# Gate GEM produced by Fujikura company



- Hole size  
F-side 316 μm  
B-side 302 μm
- Pitch 330 μm

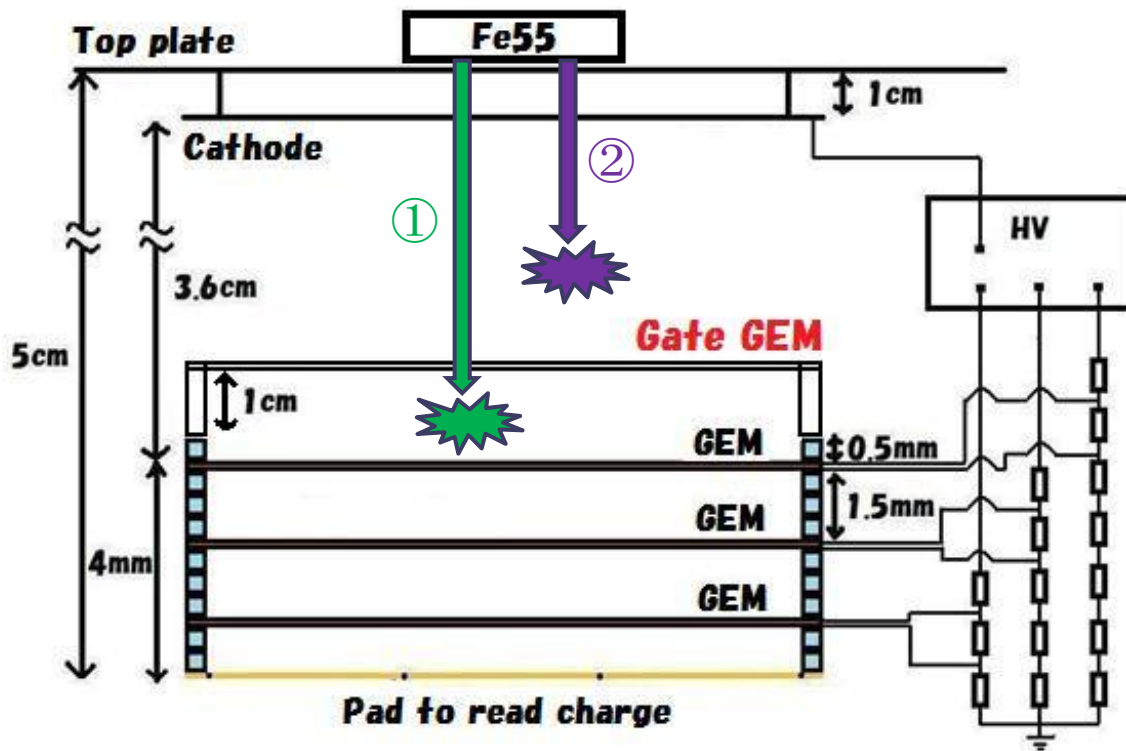
This sample is in this case.

hole size(μm)	pitch (μm)	aperture ratio (%)
300	390	53.60946746
300	360	62.91666667
300	330	74.87603306
300	300	90.6

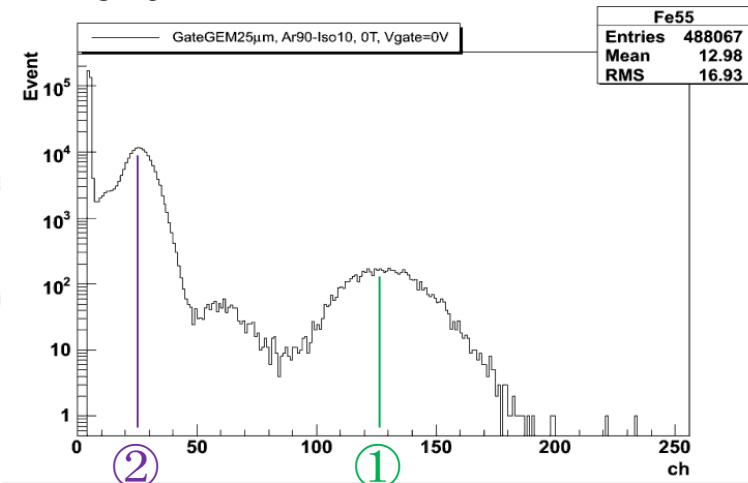
# Performance of Gate GEM

- Ions can be stopped easily.
- Gate must provide good electron transmission, but it is not easy to improve.
- Making large aperture is a one of solution.
- The feature of precision process by YAG laser can make a bigger hole.
- We need to understand gate performance not only form data also from simulation.

# Measurement of the electron transmission



Event



Interaction process ① is 100% transmission.  
We can find transmission by this equation.

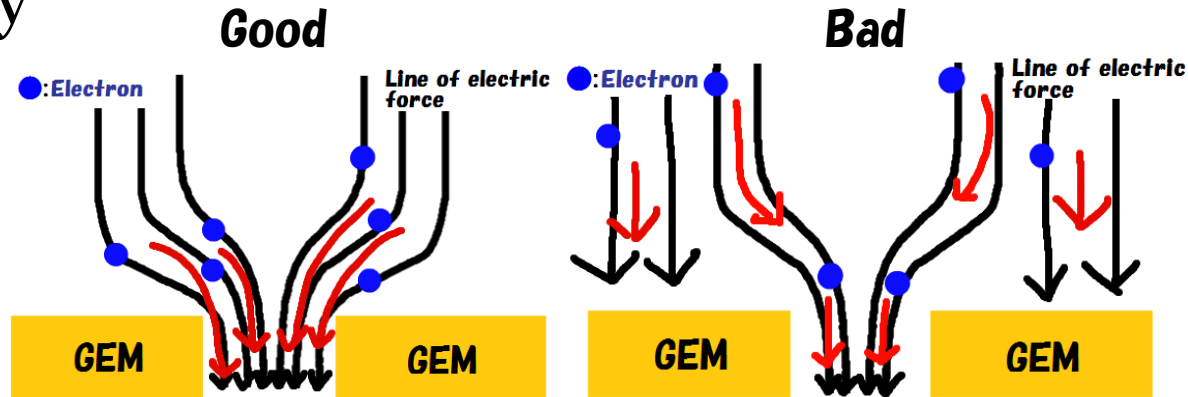
$$T = \frac{\text{②}}{\text{①}}$$

We will measure the transmission of new gate soon.

# Collection efficiency and Extraction efficiency

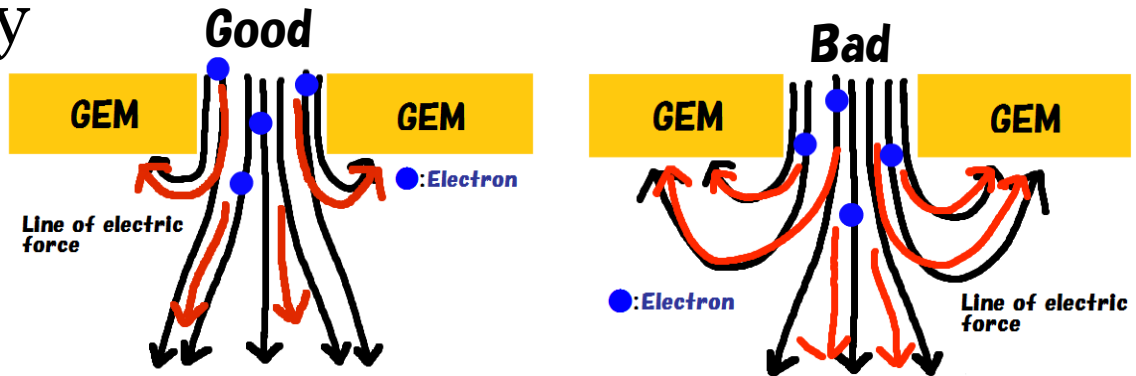
- Collection efficiency

$$C = \frac{n_{\text{Hole}}}{n_{\text{Drift or Transfer}}}$$



- Extraction efficiency

$$E = \frac{n_{\text{Transfer or Induction}}}{n_{\text{Hole}}}$$



$n_{\text{Hole}}$  : The number of electrons that go into the hole

$n_{\text{Drift or Transfer}}$  : The number of electron that is in drift region or transfer region

$n_{\text{Transfer or Induction}}$  : The number of electrons that go out of the hole

# Transmission

Electron transmission is given by this equation

$$T = \frac{n_{\text{Transfer or Induction}}}{n_{\text{Drift or Transfer}}} (= C \times E)$$

Aperture of Gate GEM have to be high, because we want to get good transmission.

UV-YAG laser technology has high accuracy of making a hole.

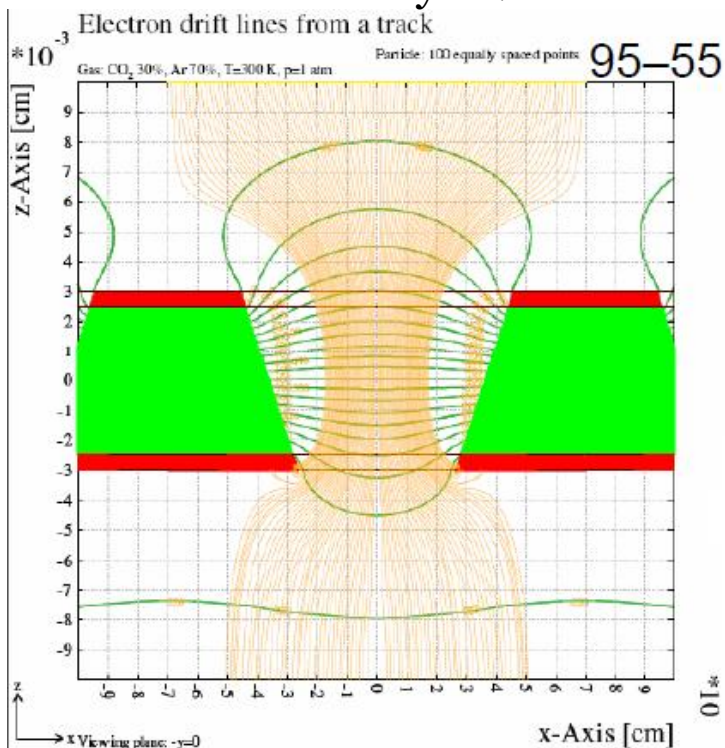
We expect that we can get high aperture of Gate GEM.



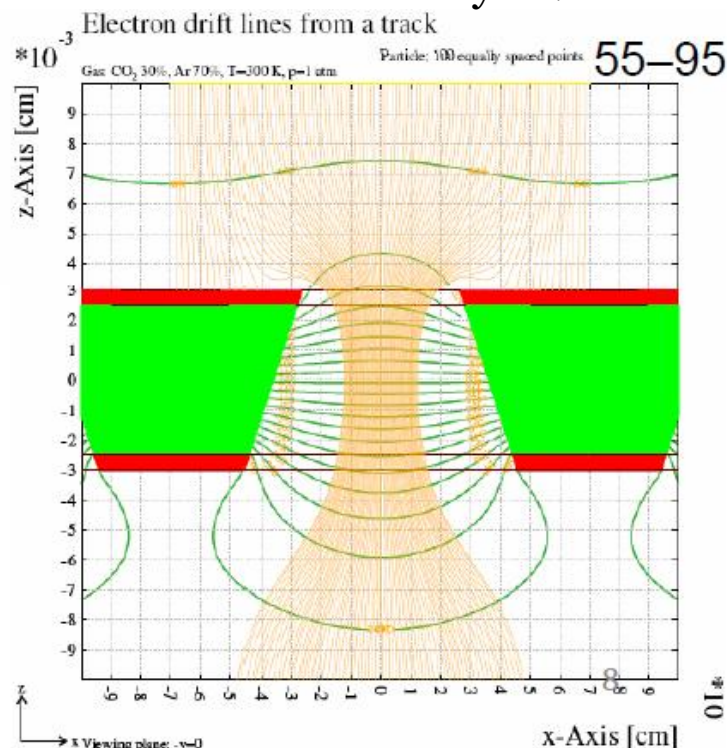
We will check how we can apply this technology of Fujikura company.

# Electric field

When upper electrode is F-side, collection efficiency is good. But extraction efficiency is bad.



When upper electrode is B-side, Extraction efficiency is good. But collection efficiency is bad.

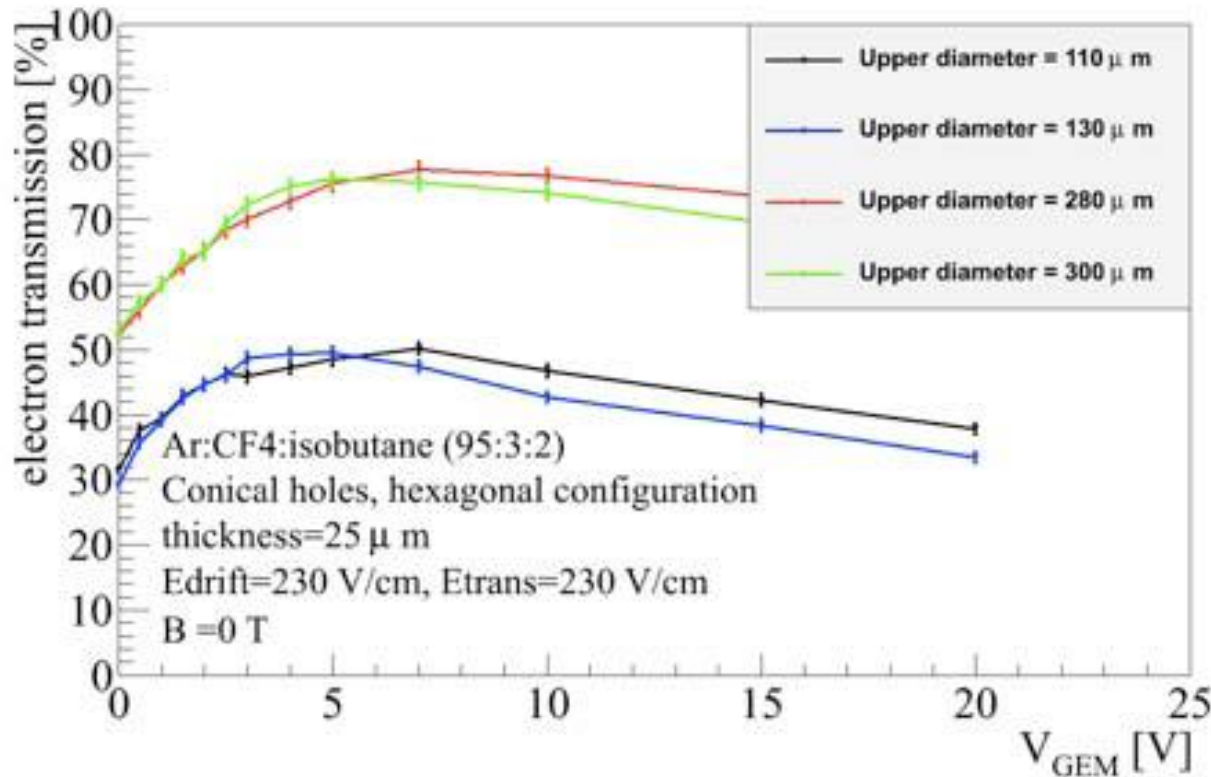


- Do Fujikura Gate GEMs have enough electron transmission?
- We have to study effect of different hole size at each side.
- Next page is result of Philippe's simulation.



# Philippe's simulation for Fujikura Gate GEM

pitch 140um/330um  
20um diff. in diam.



This graph shows Philippe's simulation for Fujikura gate GEM.

Red line means upper electrode is F-side.  
Green line means upper electrode is B-side.

In this case is using T2K gas.

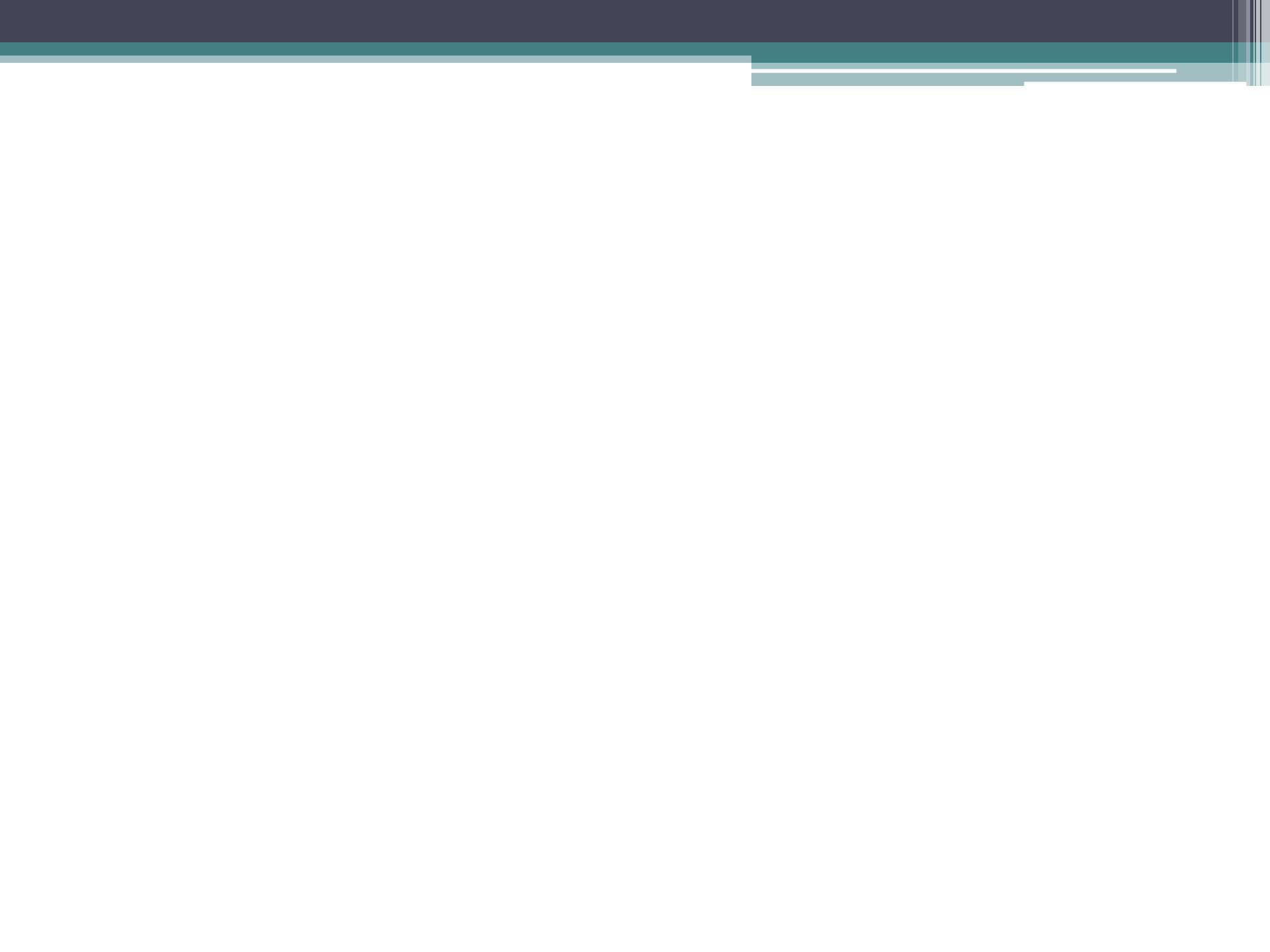
According to this result, both side is not so different.

We have to compare experimental data and this result.

# Summary

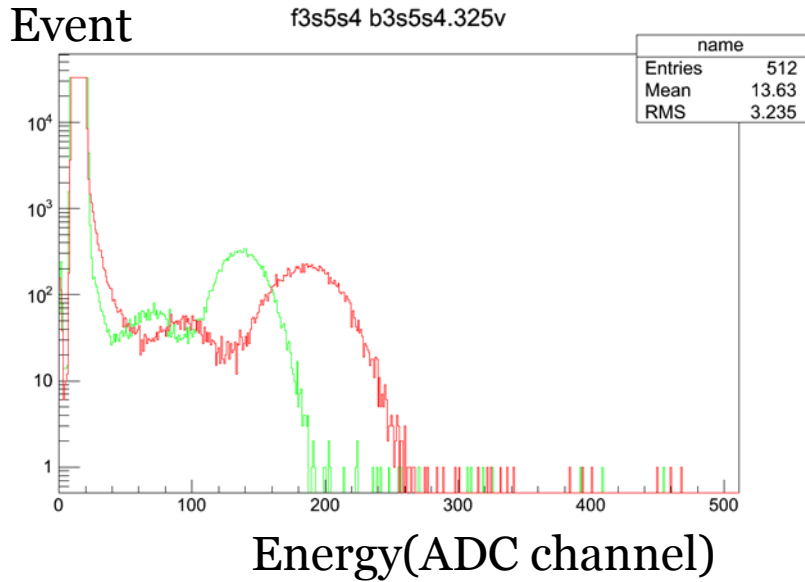
- Fujikura GEM have enough gain.
- UV-YAG laser technology has high accuracy of making a hole.
- We apply this technology to make gating system.
  
- We will measure the transmission of new gate soon, and compare the data to simulation result to understand performance of gate GEM.

Thank you!



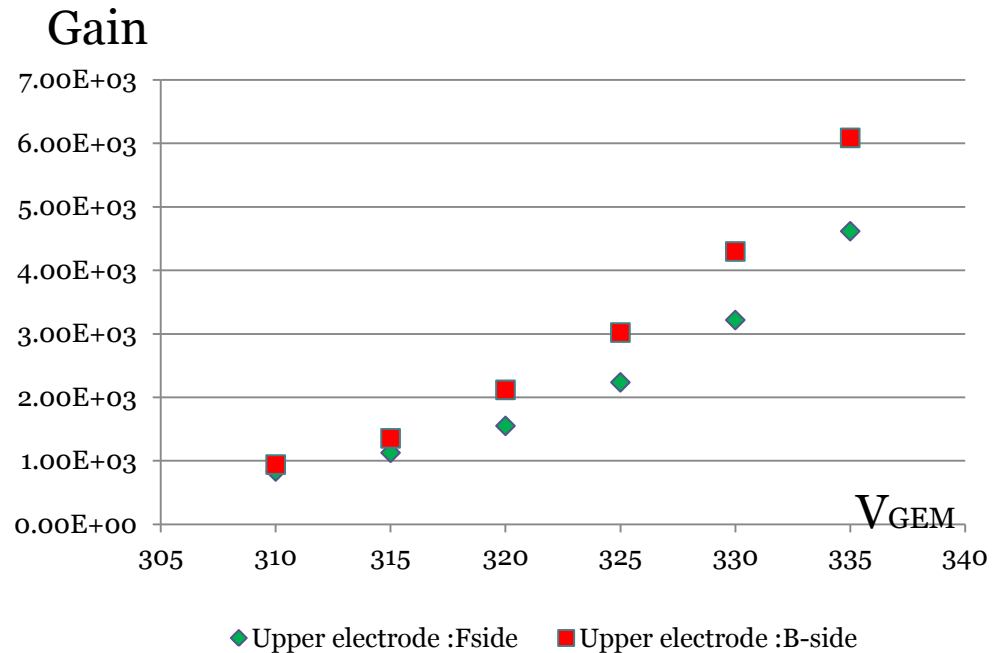
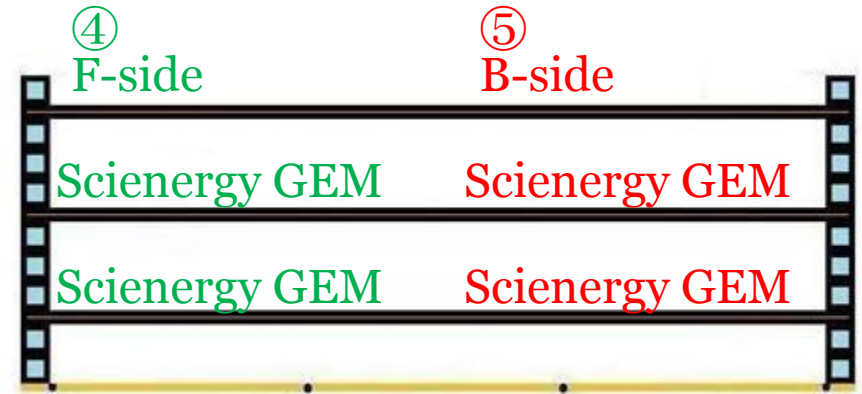
Back up

# Data2



Gain of comparison condition⑤ is bigger than comparison condition④.

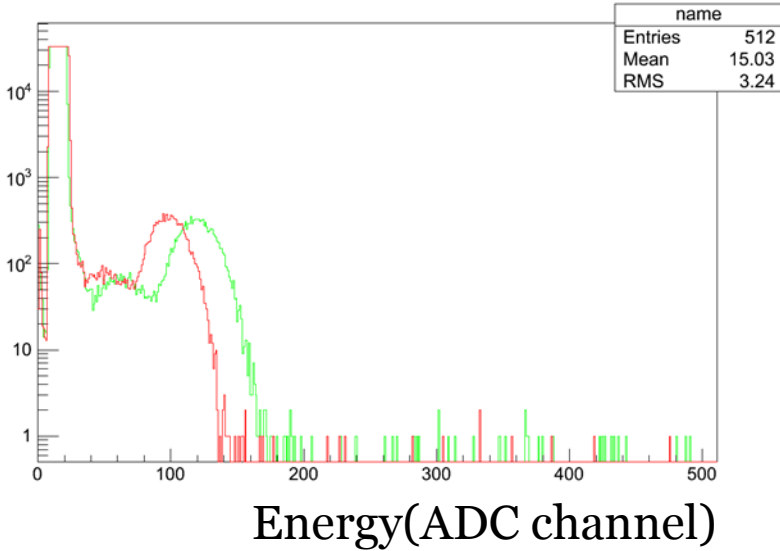
## Comparison condition



# Data3

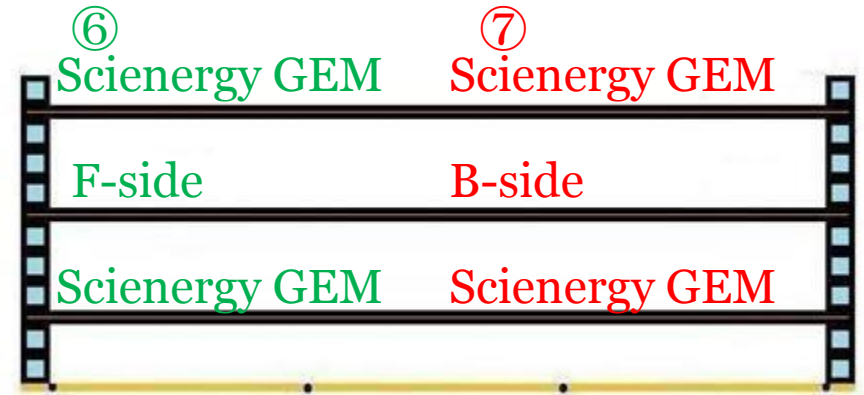
Event

s5f3s4 s5b3s4.325v

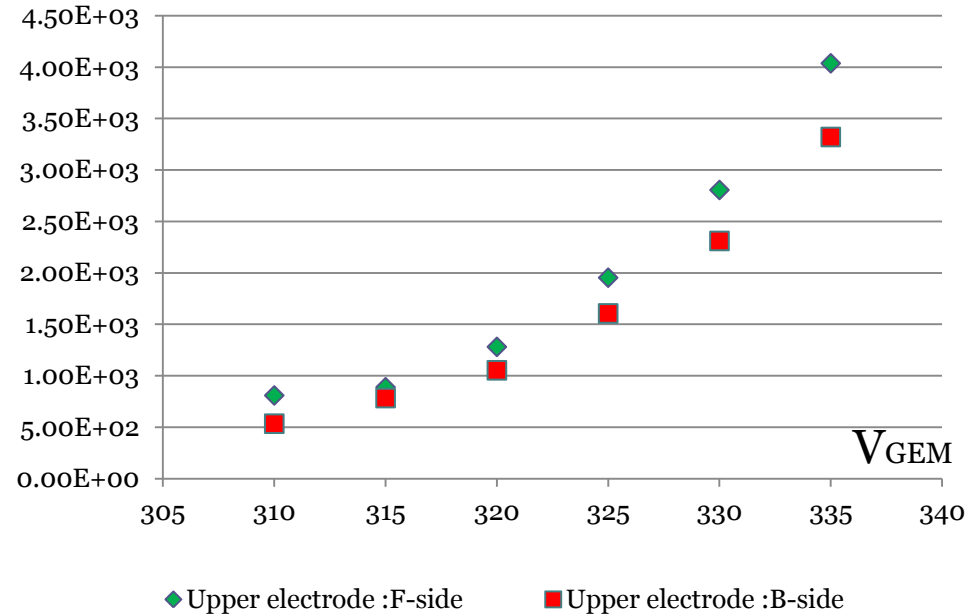


Gain of comparison condition⑥ is bigger than comparison condition⑦.

Comparison condition



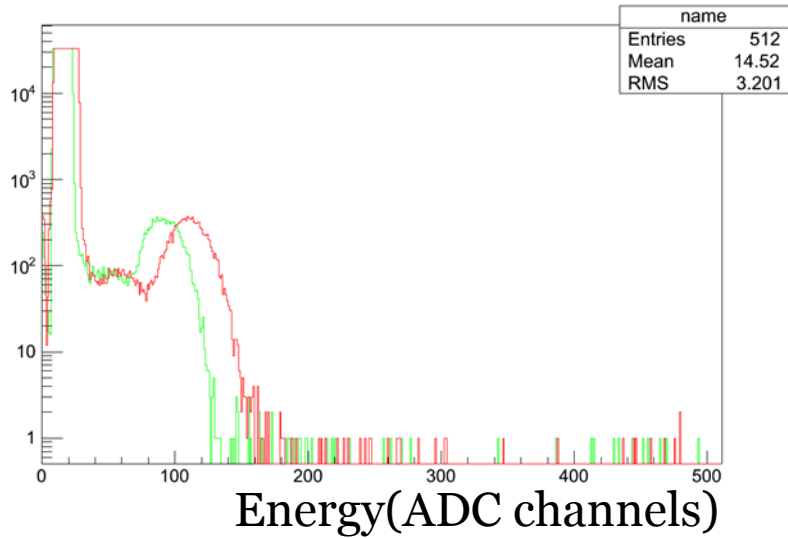
Gain



# Data4

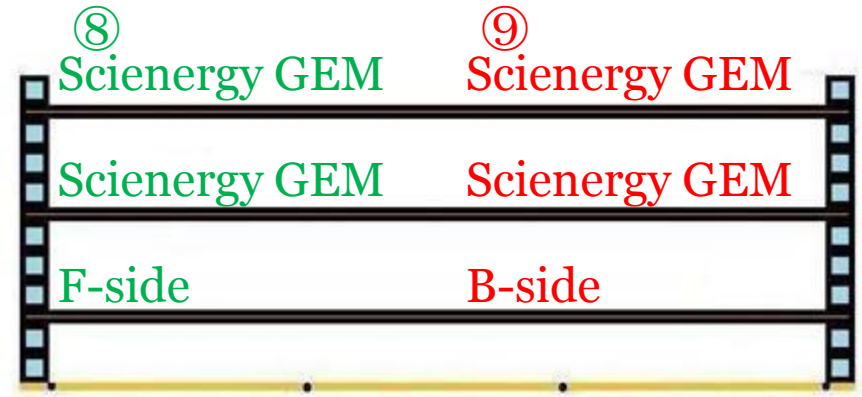
Event

s5s4f3 s5s4b3.325v



Gain of comparison condition⑨ is bigger than comparison condition⑧.

Comparison condition



Gain

